L Number	Hits	Search Text	DB	Time stamp
1	0	(mems! or (micro adj (electromechanical or	IBM_TDB	2004/05/13 15:08
		electromechanically)) or microelectromechanical or		
		microelectromechanically or micro-electromechanical or		
		micro-electromechanically) and ((SPM or afm or (((scanning		
		adj probe) or (atomic adj force)) adj (microscope or		
		microscopy))) with ((fluid or fluidic or fluent or gas or		
		gaseous) near5 (channel or channelled or channelling)))		
2	0	(mems! or (micro adj (electromechanical or	US-PGPUB	2004/05/13 15:22
_ ,	·	electromechanically)) or microelectromechanical or	03 1 31 02	200 1/05/15 15.22
		microelectromechanically or micro-electromechanical or		
		micro-electromechanically) and ((SPM or afm or (((scanning		
		adj probe) or (atomic adj force)) adj (microscope or		
		microscopy))) with ((fluid or fluidic or fluent or gas or		
_	_	gaseous) near5 (channel or channelled or channelling)))		
3	0	(mems! or (micro adj (electromechanical or	EPO	2004/05/13 15:06
		electromechanically)) or microelectromechanical or		
		microelectromechanically or micro-electromechanical or		
		micro-electromechanically) and ((SPM or afm or (((scanning		
		adj probe) or (atomic adj force)) adj (microscope or		
		microscopy))) with ((fluid or fluidic or fluent or gas or		
		gaseous) near5 (channel or channelled or channelling)))		
4	0	(mems! or (micro adj (electromechanical or	JPO	2004/05/13 15:07
'	v	electromechanically)) or microelectromechanical or	31 0	200 1/05/15 15:07
j		microelectromechanically or micro-electromechanical or		
		micro-electromechanically of finicro-electromechanical of micro-electromechanically) and ((SPM or afm or (((scanning		
		adj probe) or (atomic adj force)) adj (microscope or		
		microscopy))) with ((fluid or fluidic or fluent or gas or		
_		gaseous) near5 (channel or channelled or channelling)))		
5	0	(mems! or (micro adj (electromechanical or	DERWENT	2004/05/13 15:07
		electromechanically)) or microelectromechanical or		
		microelectromechanically or micro-electromechanical or		
		micro-electromechanically) and ((SPM or afm or (((scanning		}
		adj probe) or (atomic adj force)) adj (microscope or		
		microscopy))) with ((fluid or fluidic or fluent or gas or		
		gaseous) near5 (channel or channelled or channelling)))		
6	0	(mems! or (micro adj (electromechanical or	USOCR	2004/05/13 15:07
.		electromechanically)) or microelectromechanical or		200 1,00, 20 2010,
		microelectromechanically or micro-electromechanical or		
		•		
		micro-electromechanically) and ((SPM or afm or (((scanning		
		adj probe) or (atomic adj force)) adj (microscope or	İ	
		microscopy))) with ((fluid or fluidic or fluent or gas or		
	_	gaseous) near5 (channel or channelled or channelling)))		
7	0	(mems! or (micro adj (electromechanical or	USPAT	2004/05/13 15:07
		electromechanically)) or microelectromechanical or		
		microelectromechanically or micro-electromechanical or		
	1	micro-electromechanically) and ((SPM or afm or (((scanning		
		adj probe) or (atomic adj force)) adj (microscope or		
		microscopy))) with ((fluid or fluidic or fluent or gas or		
		gaseous) near5 (channel or channelled or channelling)))		
8	0	(SPM or afm or (((scanning adj probe) or (atomic adj force))	IBM_TDB	2004/05/13 15:10
	ŭ	adj (microscope or microscopy))) with ((fluid or fluidic or	1511_155	200 1,00,10 10:10
		fluent or gas or gaseous) near5 (channel or channelled or		
	_	channelling))	LIC DCDUD	2004/05/12 15 00
9	0	(SPM or afm or (((scanning adj probe) or (atomic adj force))	US-PGPUB	2004/05/13 15:09
		adj (microscope or microscopy))) with ((fluid or fluidic or		
		fluent or gas or gaseous) near5 (channel or channelled or		
1		channelling))		
10	0	(SPM or afm or (((scanning adj probe) or (atomic adj force))	EPO	2004/05/13 15:09
		adj (microscope or microscopy))) with ((fluid or fluidic or		
		fluent or gas or gaseous) near5 (channel or channelled or		
1		channelling))		

11	. 0	(SPM or afm or (((scanning adj probe) or (atomic adj force))	JPO	2004/05/13 15:09
		adj (microscope or microscopy))) with ((fluid or fluidic or fluent or gas or gaseous) near5 (channel or channelled or		
		channelling))		
12	0	(SPM or afm or (((scanning adj probe) or (atomic adj force))	DERWENT	2004/05/13 15:09
		adj (microscope or microscopy))) with ((fluid or fluidic or	DERWEIN	2001/05/15 15:05
		fluent or gas or gaseous) near5 (channel or channelled or		
		channelling))		
13	0	(SPM or afm or (((scanning adj probe) or (atomic adj force))	USOCR	2004/05/13 15:09
		adj (microscope or microscopy))) with ((fluid or fluidic or		
		fluent or gas or gaseous) near5 (channel or channelled or		
		channelling))		2004/05/42 45 00
14	0	(SPM or afm or (((scanning adj probe) or (atomic adj force))	USPAT	2004/05/13 15:09
		adj (microscope or microscopy))) with ((fluid or fluidic or fluent or gas or gaseous) near5 (channel or channelled or		
		channelling))		
15	0	(SPM or afm or (((scanning adj probe) or (atomic adj force))	IBM_TDB	2004/05/13 15:10
10		adj (microscope or microscopy))) and ((fluid or fluidic or	1011_100	2001/05/15 15:10
		fluent or gas or gaseous) near5 (channel or channelled or		
		channelling))		,
16	103	(SPM or afm or (((scanning adj probe) or (atomic adj force))	US-PGPUB	2004/05/13 15:13
		adj (microscope or microscopy))) and ((fluid or fluidic or		
		fluent or gas or gaseous) near5 (channel or channelled or		
17		channelling))	LIC DCDLIB	2004/05/12 15:12
17	1	(SPM or afm or (((scanning adj probe) or (atomic adj force)) adj (microscope or microscopy))) same ((fluid or fluidic or	US-PGPUB	2004/05/13 15:13
		fluent or gas or gaseous) near5 (channel or channelled or		
		channelling))		
18	0	(SPM or afm or (((scanning adj probe) or (atomic adj force))	EPO	2004/05/13 15:13
		adj (microscope or microscopy))) same ((fluid or fluidic or		' '
		fluent or gas or gaseous) near5 (channel or channelled or		
		channelling))		
19	0	(SPM or afm or (((scanning adj probe) or (atomic adj force))	EPO	2004/05/13 15:13
		adj (microscope or microscopy))) and ((fluid or fluidic or		
		fluent or gas or gaseous) near5 (channel or channelled or channelling))		
20	0	((scanning)) ((SPM or afm or (((scanning adj probe) or (atomic adj force))	JPO	2004/05/13 15:13
20	"	adj (microscope or microscopy))) and ((fluid or fluidic or	3.0	2001/05/13 13:13
		fluent or gas or gaseous) near5 (channel or channelled or		
		channelling))		
21	0	(SPM or afm or (((scanning adj probe) or (atomic adj force))	DERWENT	2004/05/13 15:14
	:	adj (microscope or microscopy))) and ((fluid or fluidic or		
		fluent or gas or gaseous) near5 (channel or channelled or		
22	42	channelling)) (SPM or afm or (((scapping adi probe) or (atomic adi force))	LISOCE	2004/05/12 15:22
22	13	(SPM or afm or (((scanning adj probe) or (atomic adj force)) adj (microscope or microscopy))) and ((fluid or fluidic or	USOCR	2004/05/13 15:22
		fluent or gas or gaseous) near5 (channel or channelled or		
		channelling))		
23	91	(SPM or afm or (((scanning adj probe) or (atomic adj force))	USPAT	2004/05/13 16:15
		adj (microscope or microscopy))) and ((fluid or fluidic or		
		fluent or gas or gaseous) near5 (channel or channelled or		
		channelling))		
24	17	(mems! or (micro adj (electromechanical or	US-PGPUB	2004/05/13 15:59
		electromechanically)) or microelectromechanical or		
		microelectromechanically or micro-electromechanical or micro-electromechanically) and ((SPM or afm or (((scanning		
		adj probe) or (atomic adj force)) adj (microscope or		
		microscopy))) and ((fluid or fluidic or fluent or gas or		
		gaseous) near5 (channel or channelled or channelling)))		
	l	gaseous/ ficults (charmer of charmened of charmening)))		1

25	16	(mems! or (micro adj (electromechanical or	USPAT	2004/05/13 15:59
		electromechanically)) or microelectromechanical or		
		microelectromechanically or micro-electromechanical or		
		micro-electromechanically) and ((SPM or afm or (((scanning		
		adj probe) or (atomic adj force)) adj (microscope or		
		microscopy))) and ((fluid or fluidic or fluent or gas or		
		gaseous) near5 (channel or channelled or channelling)))		
26	0	(SPM or afm or (((scanning adj probe) or (atomic adj force))	USPAT	2004/05/13 16:16
		adj (microscope or microscopy))) same ((fluid or fluidic or		
		fluent or gas or gaseous) near5 (channel or channelled or		
		channelling))		
27	3	(jp-07105580-\$ or jp-61133065-\$ or jp-01264403-\$).did.	DERWENT	2004/05/13 16:20
28	1	jp-01262403-\$.did.	DERWENT	2004/05/13 16:21

DERWENT-ACC-NO:

1995-188360

DERWENT-WEEK:

199525

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TITLE:

Non-volatile

information recording medium - includes

layer of silver@,

indium@, antimony@ and tellurium@

heated for recording

by creating difference from one

point to another using

scanning type tunnel microscope

probe generating

tunnel current

PATENT-ASSIGNEE: HITACHI LTD[HITA]

PRIORITY-DATA: 1993JP-0250300 (October 6,

1993)

PATENT-FAMILY:

PUB-NO

PUB-DATE

LANGUAGE

PAGES

MAIN-IPC

JP 07105580 A

N/A

April 21, 1995

004

G11B 009/04

APPLICATION-DATA:

PUB-NO

APPL-DESCRIPTOR

APPL-NO

APPL-DATE

JP 07105580A

N/A

1993JP-0250300 October 6, 1993

INT-CL (IPC): G11B009/04, H01F010/08

ABSTRACTED-PUB-NO: JP 07105580A

BASIC-ABSTRACT:

The recording type layer (3) is mounted on an electrode layer (2) formed from a high fusing point material. This electrode layer is, in turn, mounted on a conductive substrate (1).

A scanning type tunnel microscope probe carries out heating of the recording type layer to create a difference from one point to another by passing current through it. Based on the electrical conductivity of the element constituting the layer, a tunnel current flows between this layer and the electrode layer. Thus, multiple information is recorded by this process on the recording type layer.

ADVANTAGE - Enables recording of large scale information. Provides recording path of several 10 nm for single bit of data.

CHOSEN-DRAWING: Dwq.1/2

DERWENT-CLASS: T03

EPI-CODES: T03-C05; T03-C09;

DERWENT-ACC-NO:

1989-351865

DERWENT-WEEK:

198948

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TITLE:

Probe for inner

atomic force microscope - has flexible

silicon oxide-silicon

nitride plates, and provides plate

top end with needle

chip NoAbstract Dwg 2/4

PATENT-ASSIGNEE: HITACHI LTD[HITA]

PRIORITY-DATA: 1988JP-0089024 (April 13,

1988)

PATENT-FAMILY:

PUB-NO

PUB-DATE

LANGUAGE

PAGES MAIN-IPC

JP 01262403 A

N/A

October 19, 1989

004

N/A

APPLICATION-DATA:

PUB-NO

APPL-DESCRIPTOR

APPL-DATE

APPL-NO JP 01262403A

N/A

1988JP-0089024

April 13, 1988

INT-CL (IPC): G01B007/34, G01N023/00,

H01J037/08

ABSTRACTED-PUB-NO:

EQUIVALENT-ABSTRACTS:

DERWENT-CLASS: S02 S03 V05

EPI-CODES: S02-A02X; S03-E02X; S03-E06B;

V05-F01; V05-F03;

05/13/2004, EAST Version: 1.4.1